

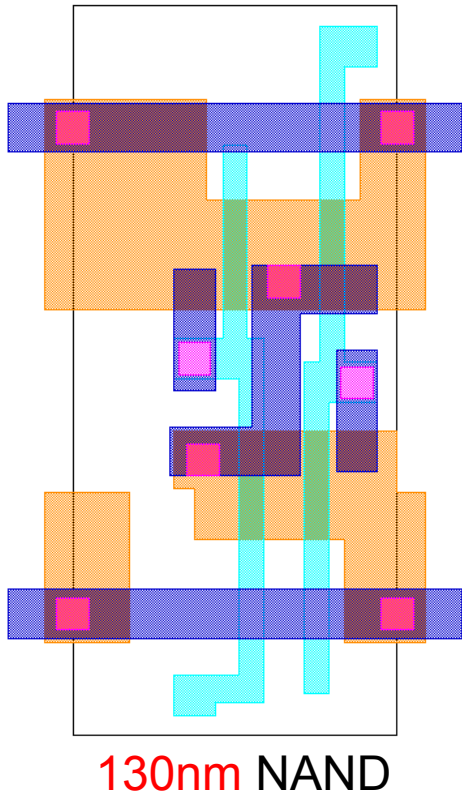
PARR: Pin Access Planning and Regular Routing for Self- Aligned Double Patterning

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Detailed Routing in Extreme Scaling

- ◆ Moore's Law => Extreme Scaling



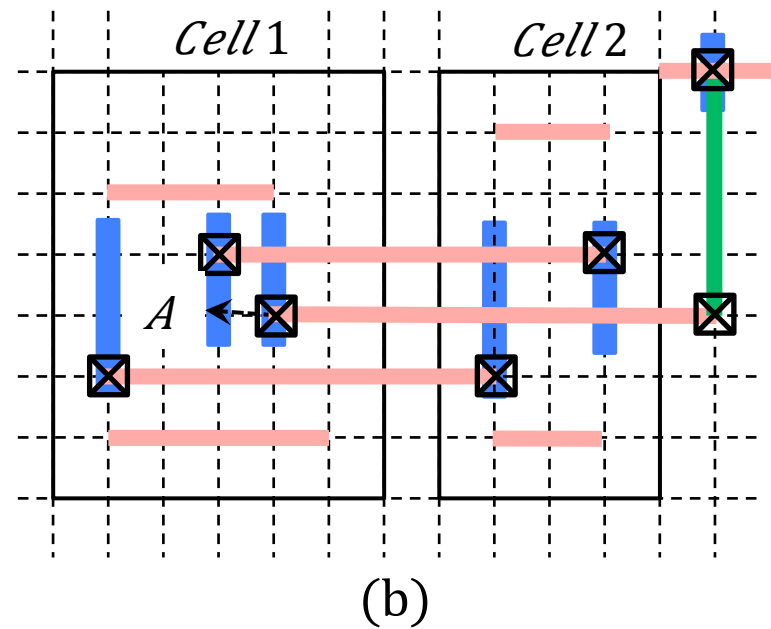
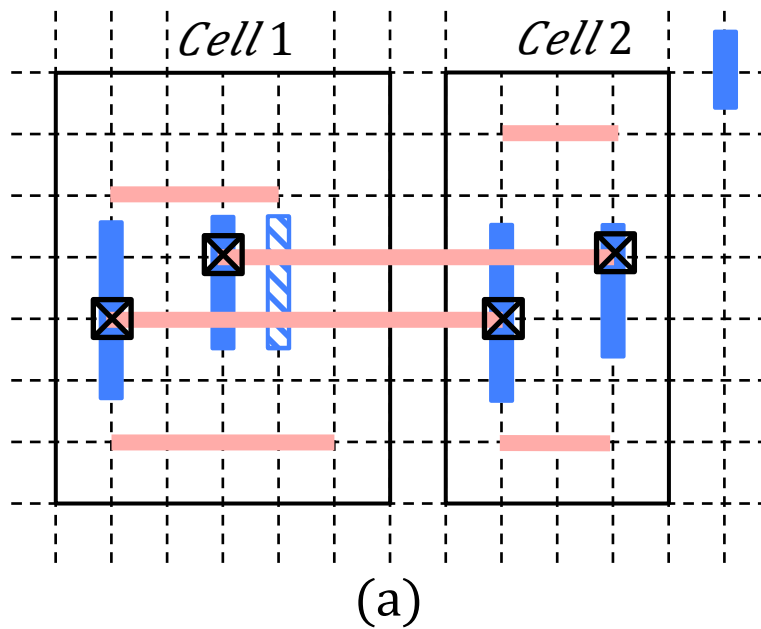
14nm NAND

[Liebmann+, SPIE'13]

- ◆ High pin density => Routability
- ◆ Less pitch => Printability

Challenge 1: Pin Accessibility

- ◆ Access Point Selection
- ◆ Net ordering



■ M1 pin

□ Cell boundary

— M2 wire

⊗ Via

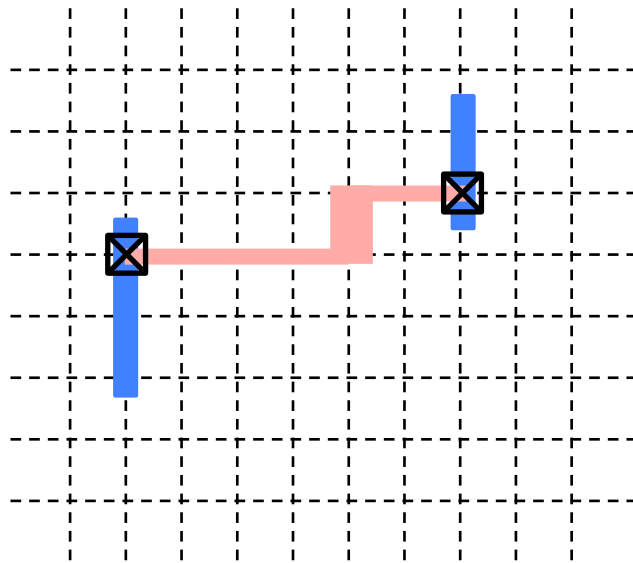
— M3 wire

▨ blocked pin

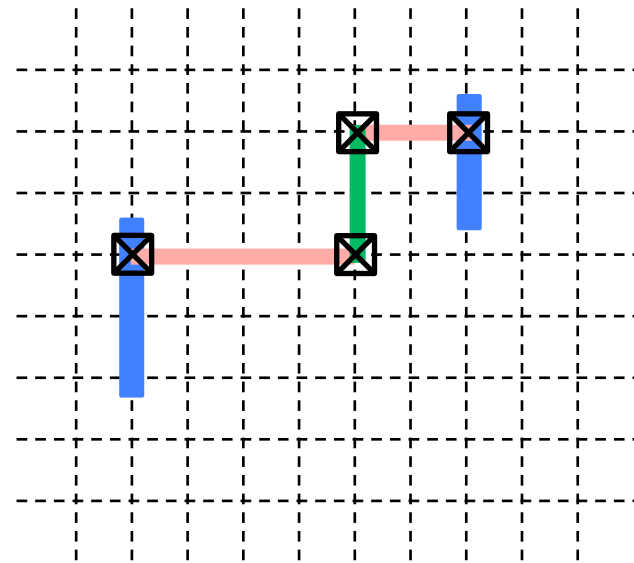
Challenge 2: Printability

◆ 2-D routing vs 1-D routing

- › 2D: Larger design space; but restrictive design rules
- › 1D: better printability; but extra vias



2-D



1-D

■ M1 pin ■ M3 wire ■ M2 wire ⊠ Via

Previous Works



- ◆ Standard cell pin access [Xu+,ISPD'14] [Ye+,GLSVLSI'15]
- ◆ Pin access for placement [Taghavi+,ICCAD'10]
- ◆ Pin access for detailed routing
[Ozdal,TCAD'09] [Nieberg+,DAC'11] [Qi+,ICCD'14]
- ◆ SADP-aware detailed routing
[Mirsaeedi+,SPIE'11] [Gao+,ISPD'12] [Du+,DAC'13] [Liu+,DAC'14]

- ◆ **Our contributions**
 - › **Pin access planning** and SADP-friendly **1-D routing**
 - › **Handshake** std-cell pin access with detailed routing to improve pin accessibility

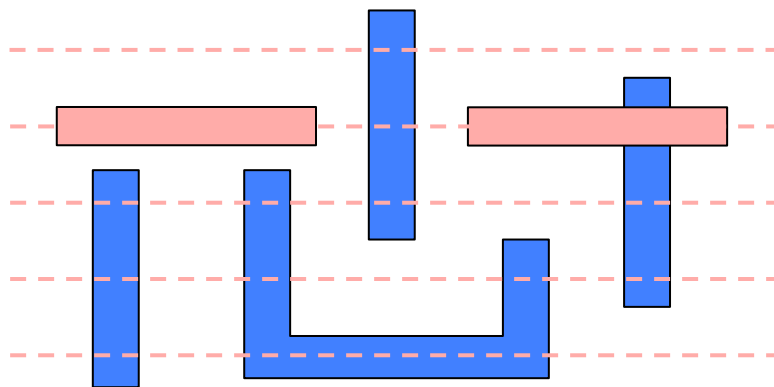
Problem Formulation



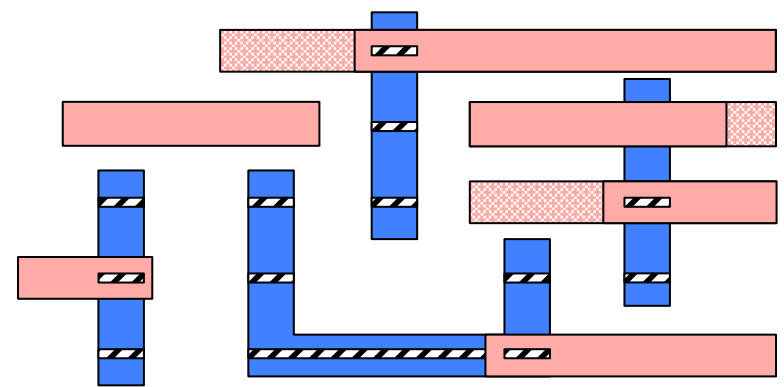
- ◆ **Input:** a netlist, pin access Look-Up Table (LUT) of the library and a set of design rules
- ◆ **Output:** design rule clean routing results
- ◆ **Objective:** perform the regular routing and design rule legalization simultaneously to achieve SADP-friendly routing results

Intra-Cell Pin Access [X. Xu+, ISPD'14]

- ◆ Intra-cell pin access design
- ◆ Store in look-up table (LUT)



(a)

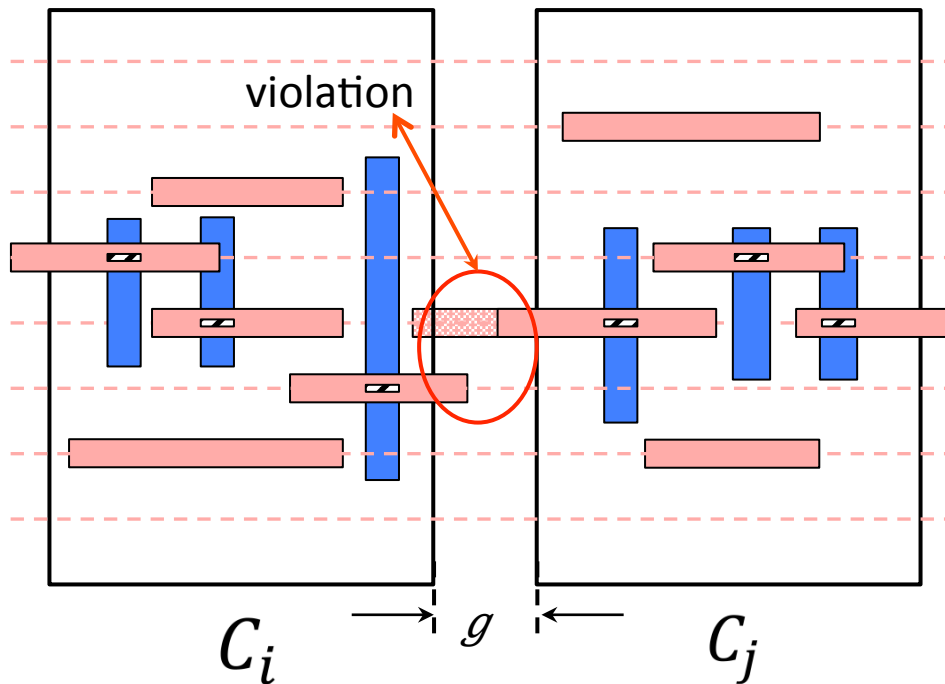


(b)



This Work: **Inter-Cell Pin Access**

- ◆ C_i is placed to the left of C_j with the gap as g
- ◆ Intra-cell pin access for C_i and C_j interferes



--- M2 routing track

▨ M2 hit point

■ M1 pin

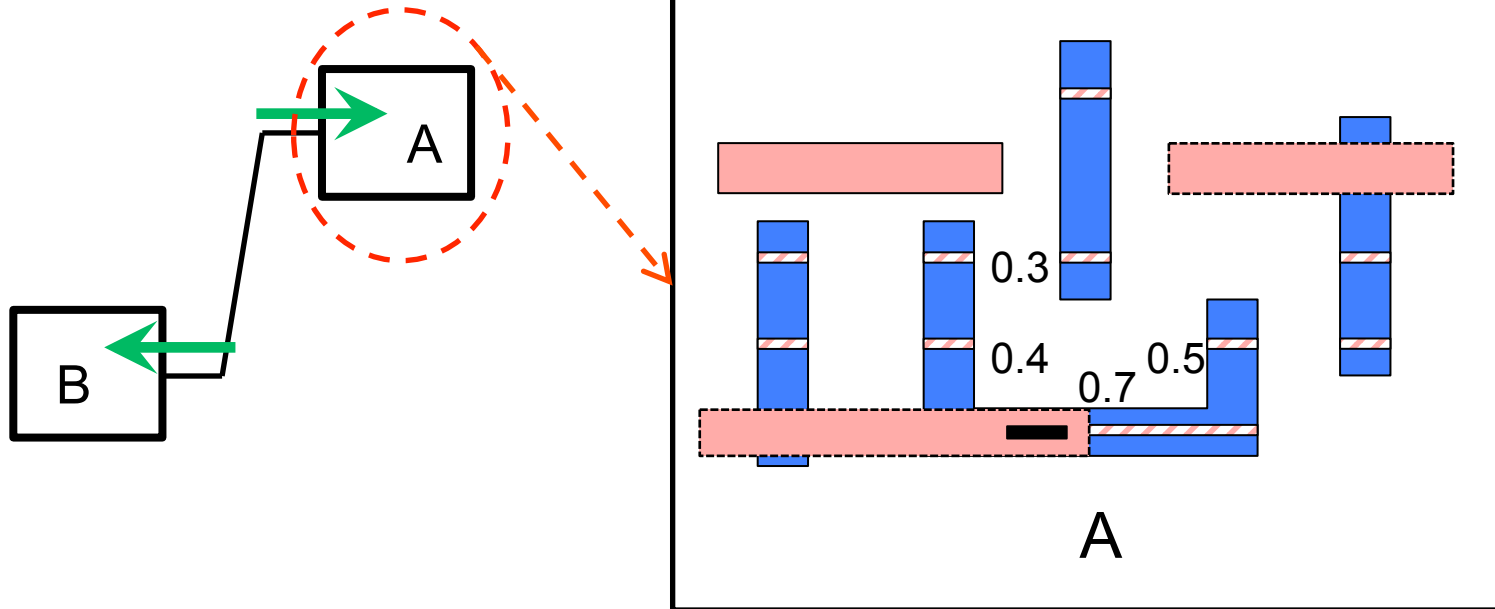
■ M2 wires

□ Cell boundary

▨ M2 extension

Local Pin Access Planning

- ◆ Dynamic hit point scoring
 - › Source pin (A) and target pin (B)
 - › Assign higher score to the hit point with larger number of intra-cell pin access solutions

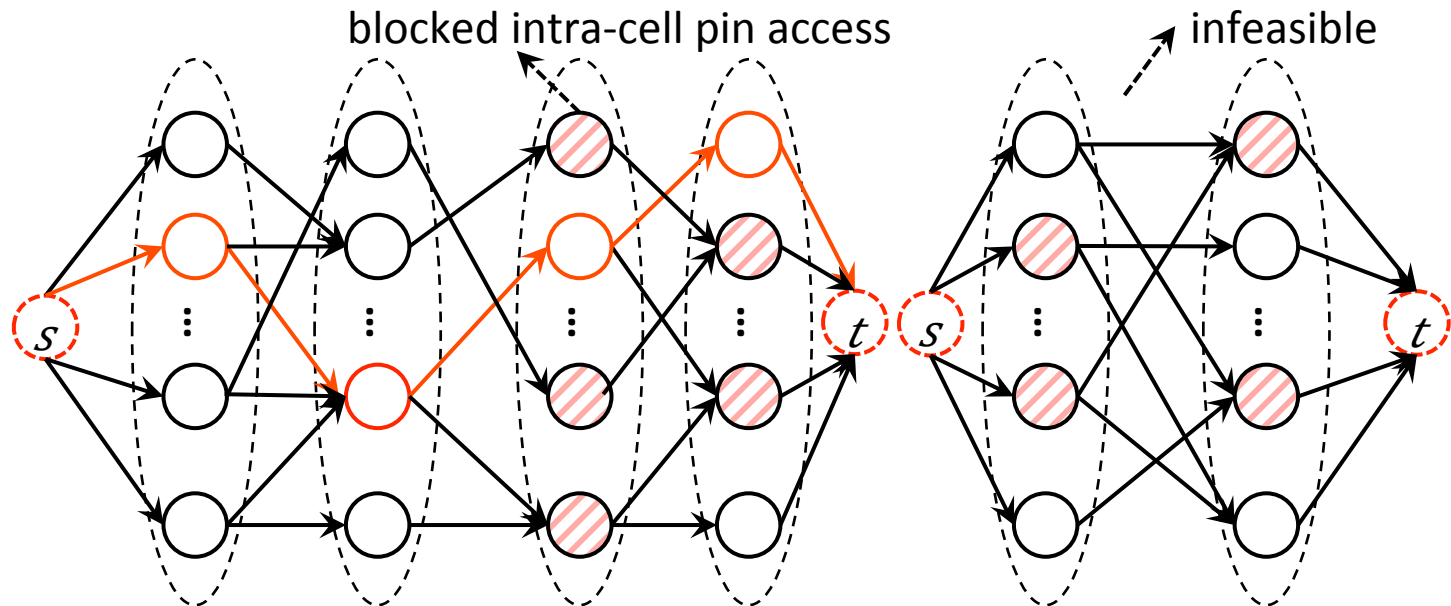
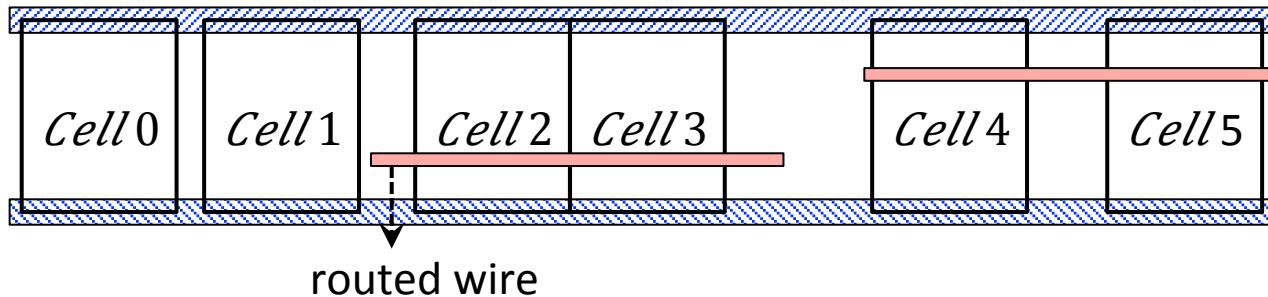


Global Pin Access Planning

- ◆ Net weight for ordering – smaller order goes first
 - › $\text{Order}(\text{net}) = \text{HPWL}(\text{net}) * (1 + \alpha * \min\{\text{hp}_s, \text{hp}_t\} + \text{Dcost}(\text{net})$
- ◆ The term: $\min\{\text{hp}_s, \text{hp}_t\}$ - minimum # of hit points for source/target pins
 - › Defer the nets with robust source and target pins
- ◆ The term $\text{Dcost}(\text{net})$ - deferring cost
 - › Maintain the s to t path existence of of PAG
 - › Preserve the pin accessibility of the remaining nets

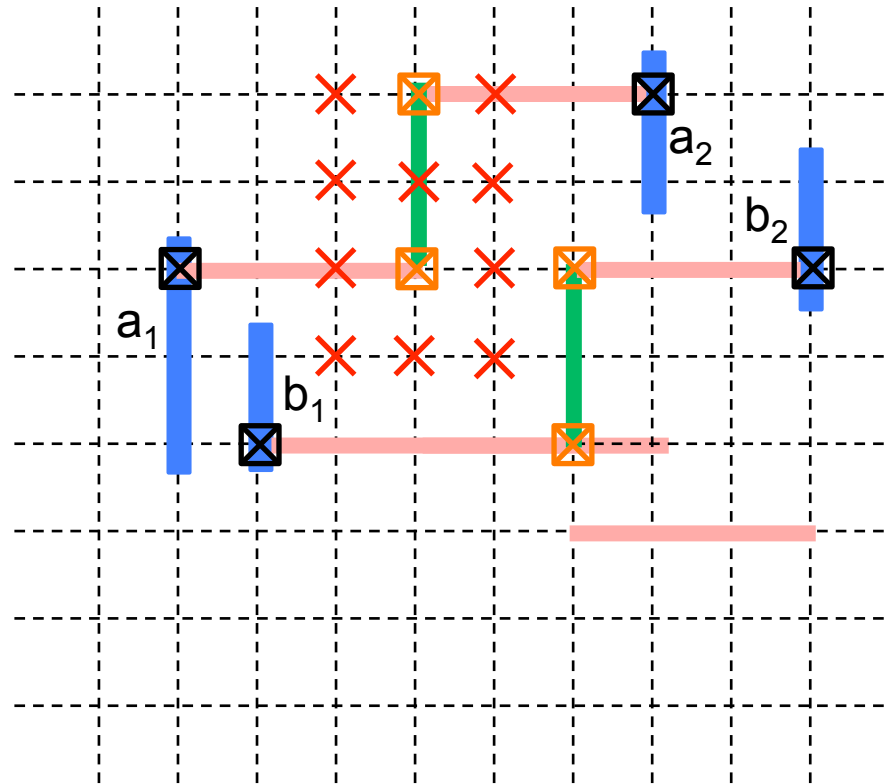
Single Row Pin Access Graph (PAG)

- ◆ Routed wires block some intra-cell pin access



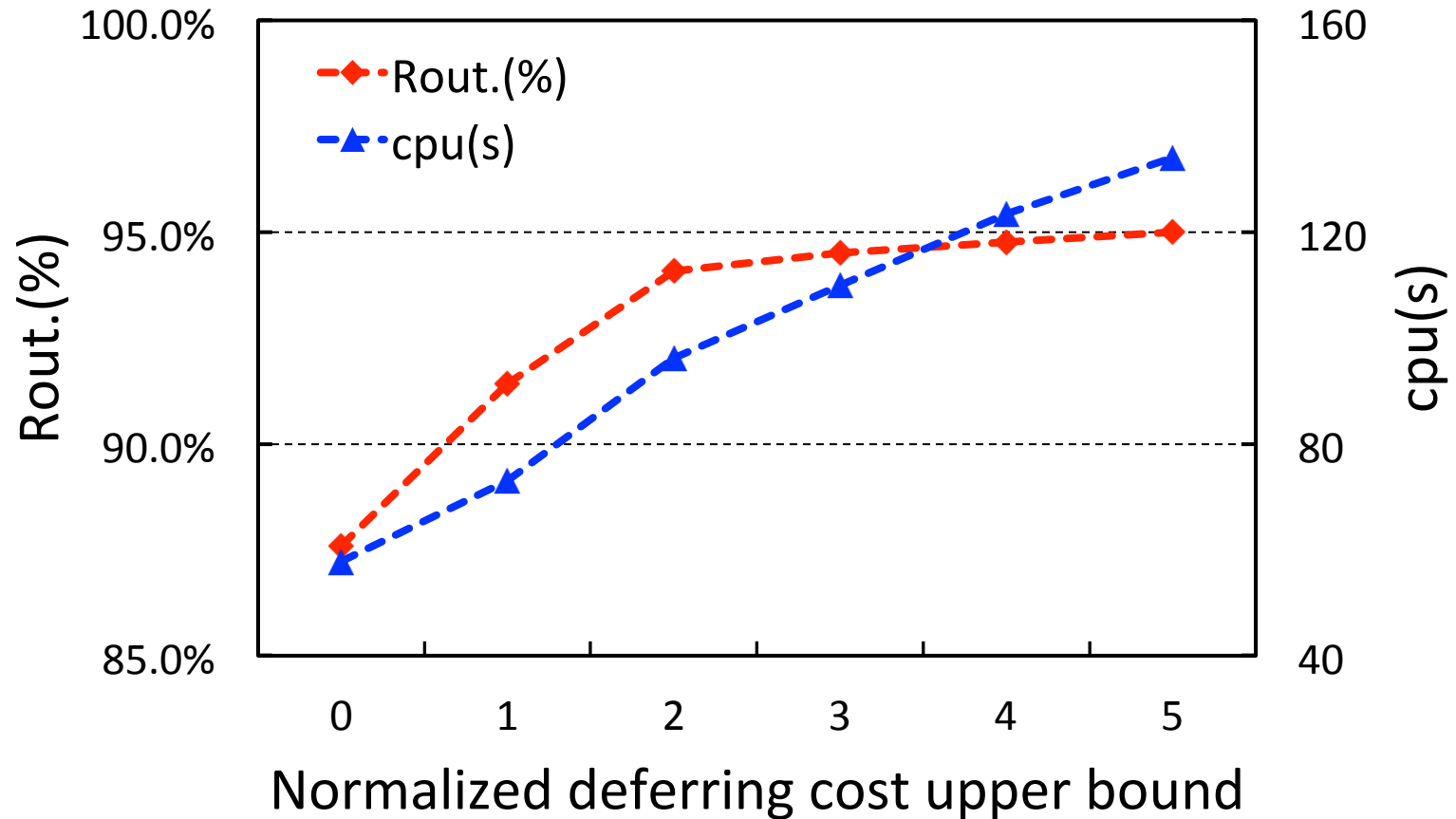
1-D Routing with Rule Legalization

- ◆ 1-D A* search
 - › Forbidden via positions

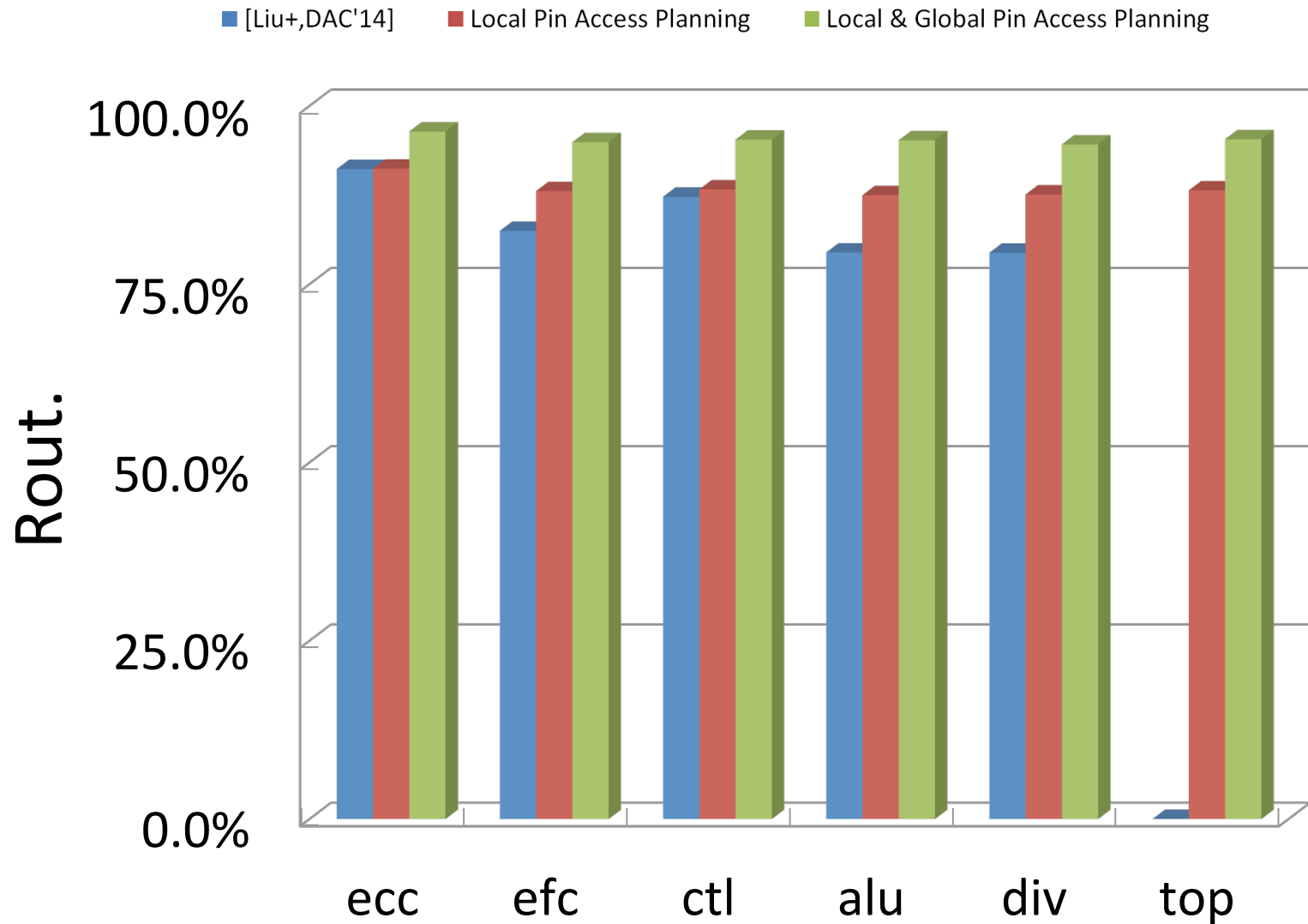


Trade-off

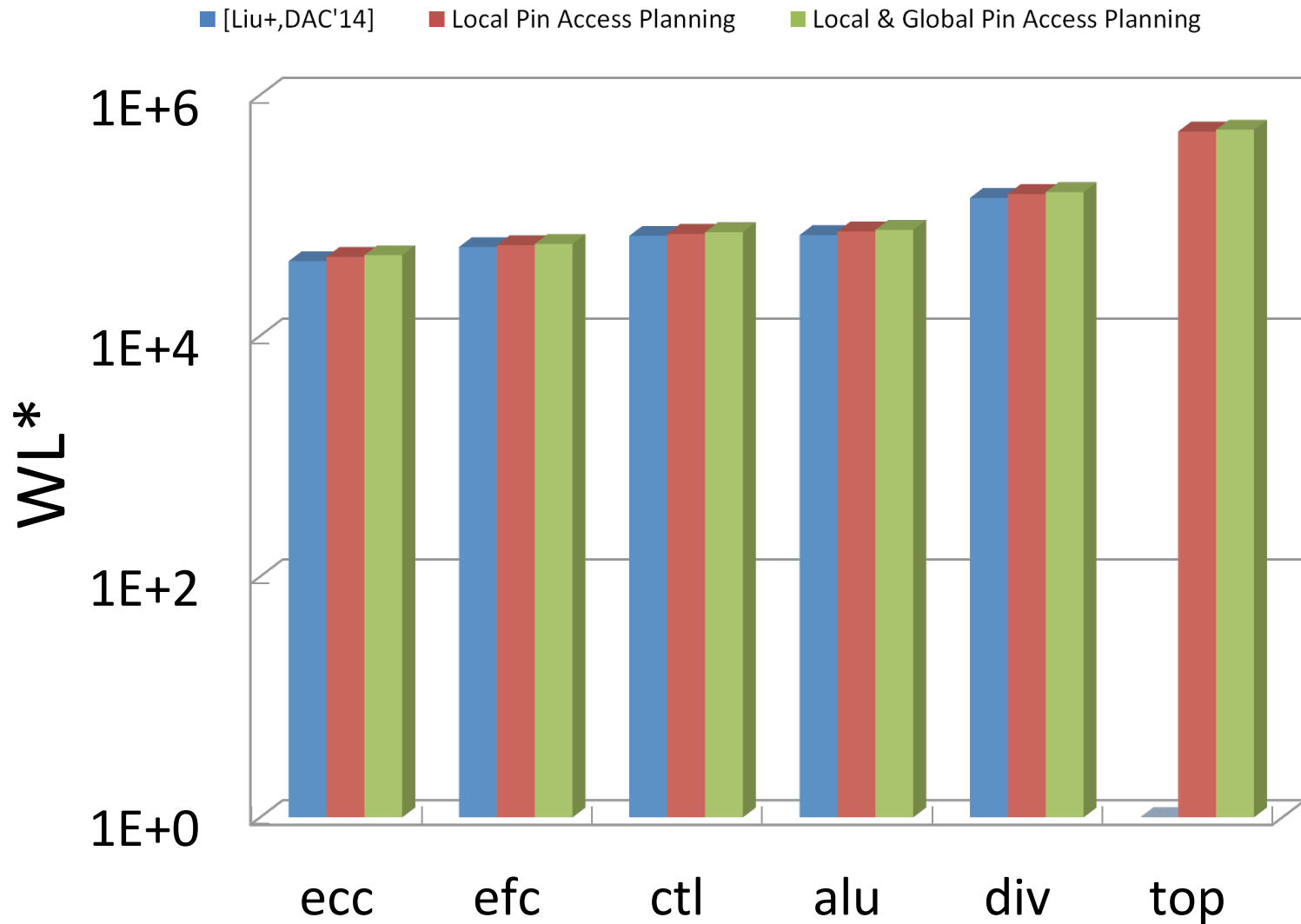
- ◆ Vary deferring cost upper bound



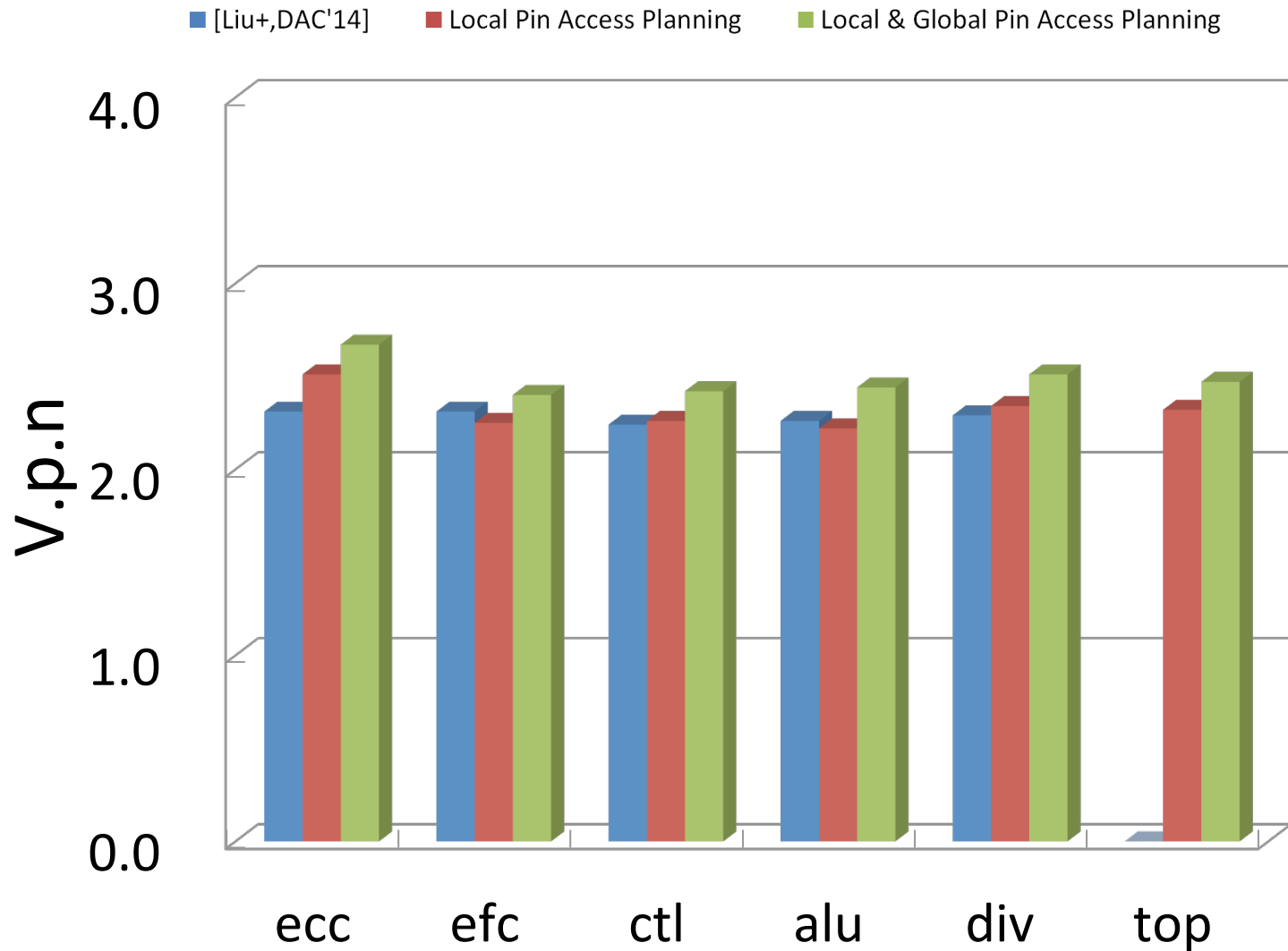
Routability Improvement



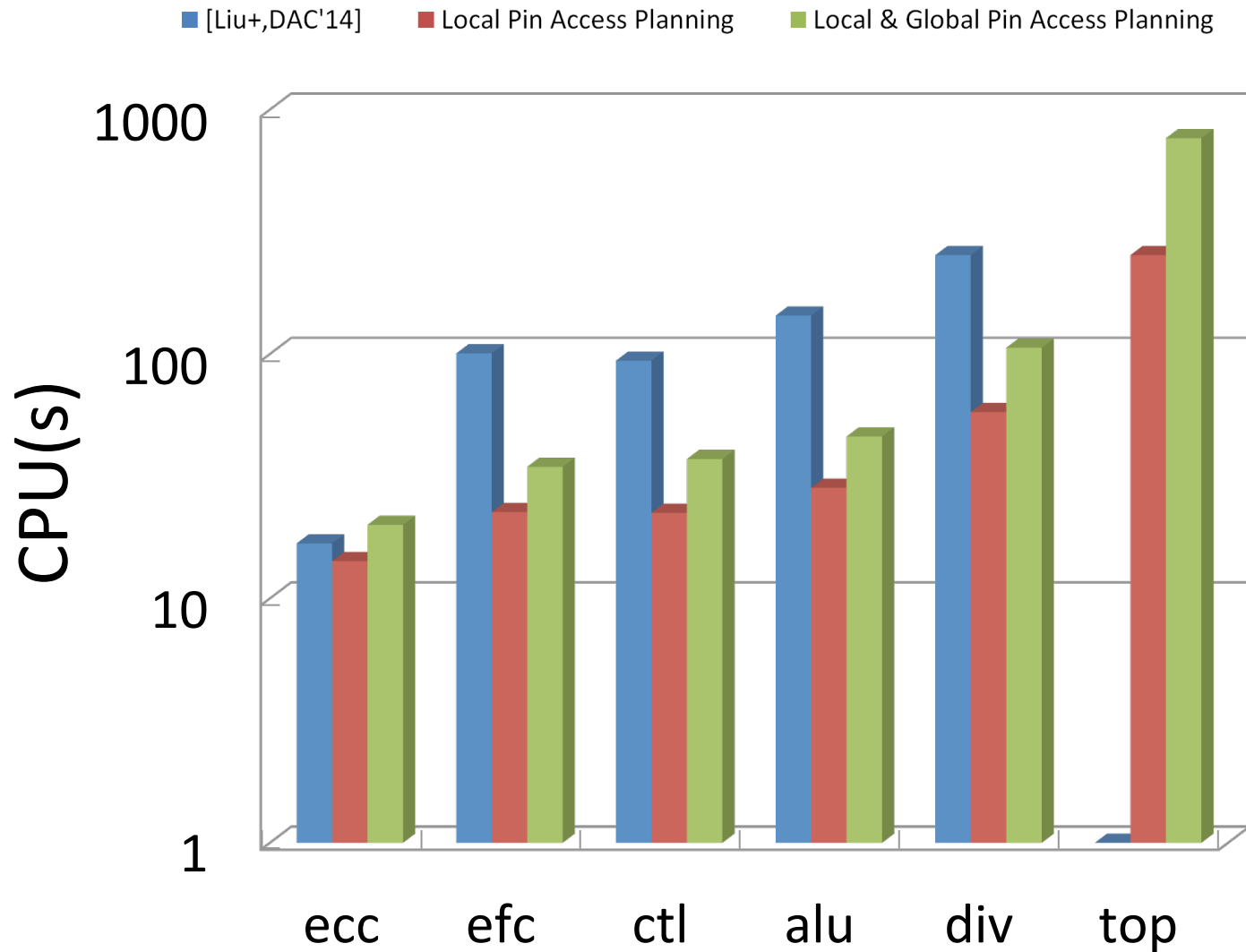
Wirelength Impact



Via Number per Routed Net (V.p.n)



Run Time Reduction



Conclusion



- ◆ Pin Accessibility Prediction
 - › Intra-cell and inter-cell
- ◆ Local and Global Pin Access Planning
- ◆ 1-D routing patterns
 - › Forbid the non-preferred direction

Thank you!

Q&A